

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20130904000 Aizu Facility as an additional FAB source for select devices in the F05 Process Change Notification / Sample Request

Date: 9/5/2013

To: Newark/Farnell PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

PCN Team SC Business Services

Phone: +1(214) 480-6037 Fax: +1(214) 480-6659

20130904000 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
TMS320F28027PTT	null
TMS320F28027PTR	null
TMS320F28027DAS	null
TMS320F28026PTS	null
TMS320F28026DAT	null
TMS320F28021DAT	null
TMS320F28020DAT	null
TMS320F28027PTS	null
TMS320F28027FPTT	null
TMS320F28027DAT	null
TMS320F28026DAS	null

Technical details of this Product Change follow on the next page(s).

PCN	Num	ber:	PC	CN2	013090400	0				PCN Date: 09/05/2013			
Title	•	Aizu Facility	y as an additional FAB source for select devices in the F05 Process										
		Contact:	PCN Manager PI			Phone	e: +1(214)480)-60	37	Dept: Quality Services			
Proposed 1 st Ship Date: 12/05/2013				Estimated Sample Availability: Date provided at sample request.									
Change Type:													
	Asse	mbly Site	☐ Assembly Proces				Assembly Materials						
	Desi				Electrical	Specification			M	Mechanical Specification			
		Site		Ц		Shipping/Labeling			_	Test Process			
		er Bump Site	☐ Wafer Bump M				ᆜ	_	Vafer Bump Process				
\boxtimes	Wafe	er Fab Site		<u> </u>	Wafer Fal			Ш	V	Vafer Fab Process			
					Part num								
_						PCN	Details						
Desc	ription	on of Change	:										
devic	This notification is to announce AIZU fabrication facility as an additional wafer FAB source for select devices in the F05 Process. The affected devices are listed in "Product Affected" section.												
		Qualified Site Process, 200			ess, warer	Dia.	Additional Site, Process, Wafer Dia. AIZU, F05 Process, 200mm						
Data	The F05 process was qualified in Aizu in June 2012. Qualification details are provided in the Qual Data Section.												
Reas	Reason for Change:												
Conti	Continuity of Supply												
Antic	ipate	ed impact or	Fo	rm	, Fit, Funct	ion, Q	uality or Relia	bil	ity	(positive / negative):			
None													
Changes to product identification resulting from this PCN:													
Current Chip Site Chip site code (20L) Chip country code (21L)													
	DP	1DM5			DM5		USA						
Addit	tional												
		p Site	Ch	Chip site code (20L)			Chip country code (21L))			
	A	IZU	CU2				JPN						
Sample product shipping label (not actual product label)													
TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 2Q: MSL '2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39 LBL: 5A (L)T0:1750 (1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$12 (P) (2P) REV: (2P) REV: (2V) 0033317 (20L) CSO: SHE (21L) CCO: USA (22L) ASO: MLA (23L) ASO: MTS													

Product Affected:			
SM02028APTT	TMS320F28021PTT	TMS320F28023DAT	TMS320F280270DAT
SM28020PTT	TMS320F280220DAS	TMS320F28023PTS	TMS320F280270PTS
SM28021PTT	TMS320F280220DAT	TMS320F28023PTT	TMS320F280270PTT
TJF026PTT	TMS320F280220PTS	TMS320F280260DAS	TMS320F28027DAS
TMS320F280200DAS	TMS320F280220PTT	TMS320F280260DAT	TMS320F28027DASR
TMS320F280200DAT	TMS320F28022DAS	TMS320F280260PTS	TMS320F28027DAT
TMS320F280200PTS	TMS320F28022DAT	TMS320F280260PTT	TMS320F28027DATR
TMS320F280200PTT	TMS320F28022PTS	TMS320F28026DAS	TMS320F28027FPTT
TMS320F28020DAS	TMS320F28022PTSR	TMS320F28026DASR	TMS320F28027PTR
TMS320F28020DAT	TMS320F28022PTT	TMS320F28026DAT	TMS320F28027PTS
TMS320F28020PTS	TMS320F280230DAS	TMS320F28026DATR	TMS320F28027PTT
TMS320F28020PTT	TMS320F280230DAT	TMS320F28026FPTT	TMS320F28KNWMX1
TMS320F28021DAS	TMS320F280230PTS	TMS320F28026PTS	TMS320SPC0200PTT
TMS320F28021DAT	TMS320F280230PTT	TMS320F28026PTT	
TMS320F28021PTS	TMS320F28023DAS	TMS320F280270DAS	

Qualification Data: Approved 8/30/2013							
This qualification has been developed for the validation of this change. The qualification data will							
validate that the proposed change meets the applicable released technical specifications.							
Qual Vehicle 1: TMS320F2802XAPT							
Wafer Fab Site: AIZU Metallization: TiN/AlCu/TiN							
Wafer Fab Process: F05 Wafer diameter: 200mm							
Qualification: Plan Test Results							
Reliability Test Conditions					Sample Size/Fail		
,	461.272				Lot#1	Lot#2	Lot#3
	1SL2/2		:00.0 ()	1000 1	540/0	-	-
· · ·	-65C/150C 500 Cycles (actual 1000 cycles) 231/0						-
*Autoclave	lave 121C/96hrs (actual 168 hours) 231/0						-
Notes: * Test requires Moisture Preconditioning							
Qualification tests "pass" on zero fails for each test							
Qual Vehicle 2: TMS320F2802XADA							
Wafer Fab Site: AIZU Metallization: TiN/AICu/TiN							
Wafer Fab Process: F05 Wafer diameter: 200mm							
Qualification: Plan Test Results							
Reliability Test Conditions Sample Size/Fail					•		
' Lot#1 Lot#2 Lot#3							
J	Preconditioning MSL2/260C 720/0						
*Temp Cycle -65C/150C 500 Cycles(actual 750 cycles) 231/0					-		
*Autoclave 121C/96hrs (actual 168 hours) 231/0							
*High Temp Storage Life	150C, 500 hours 231/0						
ESD-HBM 2	2000v 3/0 -				-		
ESD-CDM	SD-CDM 750v 3/0				-		
Latchup :						-	
Notes: * Test requires Moisture Preconditioning							
Qualification tests "pass" on zero fails for each test							

Reference Qual: F05 Process Qualification at Aizu

Qualification Data: Approved 06/2012							
This qualification has been developed for the validation of this change. The qualification data will							
validate that the proposed change meets the applicable released technical specifications.							
Qual Vehicle 1: TMS320F2803XAPN							
Wafer Fab Site: AIZU Metallization: TiN/AlCu/TiN							
Wafer Fab Process: F05 Wafer diameter: 200mm							
Qualification: Plan Test Results							
Reliability Test	Conditi	Conditions		Sample Size/Fail			
Reliability Test	Condici	0113		Lot#1	Lot#2	Lot#3	
20K W/E	20K Wri HTOL, R	ite / Erase Cycles prio TSL	1800/0	-	-		
High Temperature Op Life	125C - 1	125C - 1000 Hours			-	-	
*High Temp Storage Life	150C Ba	150C Bake - 1000 Hours			-	-	
Room Temp Storage Life 250		25C - 1000 Hours			-	-	
Package Reliability					-	-	
*Preconditioning	MSL3/2	MSL3/260C			-	-	
*THB 8		85C/85RH			-	-	
*Temp Cycle	-65C/15	-65C/150C 500 Cycles			-	-	
*Autoclave	121C/9	121C/96hrs			-	-	
ESD-HBM 2000v				231/0 15/0	-	-	
ESD-CDM 750v				6/0	-	_	
Latch up	1.5Vdd	+/-100mA 125C	6/0	-	-		
Notes: * Test requires Moisture Preconditioning							
Qualification tests "pass" on zero fails for each test							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com